TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC74AC175P, TC74AC175F, TC74AC175FN, TC74AC175FT

QUAD D-TYPE FLIP FLOP WITH CLEAR

The TC74AC175 is an advanced high speed CMOS QUAD D-TYPE FLIP FLOP fabricated with silicon gate and double-layer metal wiring C^2MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

These four flip-flops are controlled by a clock input (CK) and a clear input (\overline{CLR}).

The information data applied to the D inputs (D1 thru D4) are transferred to the outputs (Q1 thru Q4 and $\overline{Q}1$ thru $\overline{Q}4$) on the positive-going edge of the clock pulse.

Reset function is accomplished when the clear input is taken low, and all Q outputs are kept in low level regardless of other input conditions.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

FEATURES:

• High Speed······f_{MAX} = 170MHz(typ.)

at $V_{CC} = 5V$

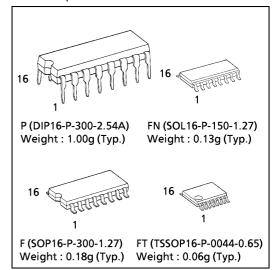
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- High Noise Immunity $V_{NIH} = V_{NIL} = 28\% V_{CC}$ (Min.)
- Symmetrical Output Impedance... $|I_{OH}| = I_{OL} = 24mA(Min.)$ Capability of driving 50Ω

transmission lines.

- Balanced Propagation Delays $\cdots t_{pLH} \simeq t_{pHL}$
- Wide Operating Voltage Range ···· V_{CC} (opr) = 2V ~ 5.5V
- Pin and Function Compatible with 74F175

(Note) The JEDEC SOP (FN) is not available in Japan.



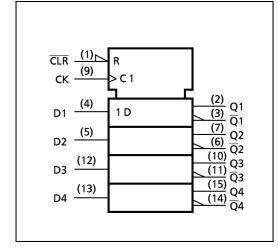
PIN ASSIGNMENT CLR 16 V_{CC} 1 15 04 01 2 Q1 3 Q4 14 13 D4 5 D2 12 D3 Q2 6 11 Q3 02 7 10 **O**3 GND 8 CK 9 (TOP VIEW)

TRUTH TABLE

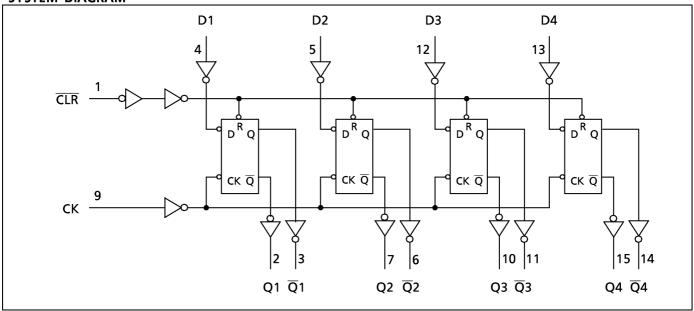
INPUTS			OUT	PUTS	FUNCTION			
CLR	D	СК	Q	Q	FONCTION			
L	Х	Х	L	Н	CLEAR			
Н	L	7	L	Н	_			
Н	Н	<u>_</u>	Н	L	_			
Н	Х	r	Qn	\overline{Q}_n	NO CHANGE			

X : Don't Care

IEC LOGIC SYMBOL



SYSTEM DIAGRAM



ABSOLUTE MAXIMUM RATINGS

DADAMETED		1/41115	
PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage Range	V _{cc}	-0.5~7.0	V
DC Input Voltage	VIN	$-0.5 \sim V_{CC} + 0.5$	V
DC Output Voltage	V _{OUT}	$-0.5 \sim V_{CC} + 0.5$	٧
Input Diode Current	I _{IK}	± 20	mΑ
Output Diode Current	I _{OK}	± 50	mΑ
DC Output Current	I _{OUT}	± 50	mA
DC V _{cc} /Ground Current	I _{cc}	± 200	mΑ
Power Dissipation	P _D	500 (DIP)*/ 180 (SOP/TSSOP)	mW
Storage Temperature	T _{stg}	−65~150	°C

*500mW in the range of Ta = -40° C ~65°C. From Ta = 65°C to 85°C a derating factor of -10mW/°C should be applied up to 300mW.

RECOMMENDED OPERATING CONDITIONS

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage	V_{CC}	2.0~5.5	>
Input Voltage	V _{IN}	0~V _{cc}	V
Output Voltage	V _{OUT}	0~V _{CC}	٧
Operating Temperature	T _{opr}	−40~85	°C
Input Rise and Fall Time	dt/dV	$0 \sim 100 \text{ (Vcc} = 3.3 \pm 0.3 \text{V)}$ $0 \sim 20 \text{ (Vcc} = 5 \pm 0.5 \text{V)}$	ns / V

DC ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION		V _{CC}	Ta = 25°C			Ta = -40~85°C		UNIT
FARAIVIETER	STIVIBUL			(V)	MIN.	TYP.	MAX.	MIN.	MAX.	OIVII
High - Level Input Voltage	V _{IH}		2.0 3.0 5.5	1.50 2.10 3.85		_ _ _	1.50 2.10 3.85		٧	
Low - Level Input Voltage	VIL		2.0 3.0 5.5		1 1 1	0.50 0.90 1.65		0.50 0.90 1.65	V	
High - Level Output Voltage	V _{OH}	V _{I N} =	$I_{OH} = -50\mu A$	2.0 3.0 4.5	1.9 2.9 4.4	2.0 3.0 4.5	_ _ _	1.9 2.9 4.4	111	V
		V _{IH} or V _{IL}	$I_{OH} = -4mA$ $I_{OH} = -24mA$ $I_{OH} = -75mA*$	3.0 4.5 5.5	2.58 3.94 —		_ _ _	2.48 3.80 3.85		V
Low - Level	V	V _{I N} =	$I_{OL} = 50 \mu A$	2.0 3.0 4.5	1 1 1	0.0 0.0 0.0	0.1 0.1 0.1	1 1 1	0.1 0.1 0.1	V
Output Voltage	V _{OL} V _{IH}	V_{IH} or V_{IL}	$I_{OL} = 12mA$ $I_{OL} = 24mA$ $I_{OL} = 75mA*$	3.0 4.5 5.5	111	111	0.36 0.36 —	111	0.44 0.44 1.65	V
Input Leakage Current	I _{IN}	$V_{IN} = V_{CC}$ or GND		5.5	-	ı	± 0.1	ı	± 1.0	
Quiescent Supply Current	I _{cc}	$V_{IN} = V_{CC}$ or GN	5.5	_	_	8.0	_	80.0	μ A	

^{* :} This spec indicates the capability of driving 50Ω transmission lines. One output should be tested at a time for a 10ms maximum duration.

TIMING REQUIREMENTS (Input $t_r = t_f = 3ns$)

PARAMETER	SYMBOL	TEST CONDI	TION	Ta = 25°C	Ta = −40~85°C	UNIT
FARAIVIETER	STIVIBUL		V _{cc} (V)	LIMIT	LIMIT	UNIT
Minimum Pulse Width (CK)	t _{W (L)} t _{W (H)}		3.3 ± 0.3 5.0 ± 0.5	7.0 5.0	7.0 5.0	
Minimum Pulse Width (CLR)	t _{W (L)}		3.3 ± 0.3 5.0 ± 0.5	7.0 5.0	7.0 5.0	
Minimum Set - up Time	ts		3.3 ± 0.3 5.0 ± 0.5	12.0 6.5	12.0 6.5	ns
Minimum Hold Time	t _h		3.3 ± 0.3 5.0 ± 0.5	0.0 0.0	0.0 0.0	
Minimum Removal Time (CLR)	t _{rem}		3.3 ± 0.3 5.0 ± 0.5	7.0 5.0	7.0 5.0	

AC ELECTRICAL CHARACTERISTICS (C_L = 50pF , R_L = 500 Ω , Input $\,t_r$ = t_f = 3ns)

PARAMETER	SYMBOL	TEST CONDITION		Ta = 25°C			Ta = −40~85°C		UNIT
FARAIVIETER	STIVIBUL		V _{CC} (V)	MIN.	TYP.	MAX.	MIN.	MAX.	וואוטן
Propagation Delay Time $(CK-Q,\overline{Q})$	t _{pLH} t _{pHL}		3.3 ± 0.3 5.0 ± 0.5		8.2 6.1	13.9 8.7	1.0 1.0	16.0 10.0	
Propagation Delay Time $(\overline{CLR} - Q, \overline{Q})$	t _{pLH} t _{pHL}		3.3 ± 0.3 5.0 ± 0.5		7.8 6.1	13.3 8.7	1.0 1.0	15.3 10.0	ns
Maximum Clock Frequency	f _{MAX}		3.3 ± 0.3 5.0 ± 0.5	40 80	80 150	_	40 80	_	MHz
Input Capacitance	C _{IN}			_	5	10	_	10	pF
Power Dissipation Capacitance	C _{PD} (1)		·	_	85	_	_	_] [

Note (1) C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

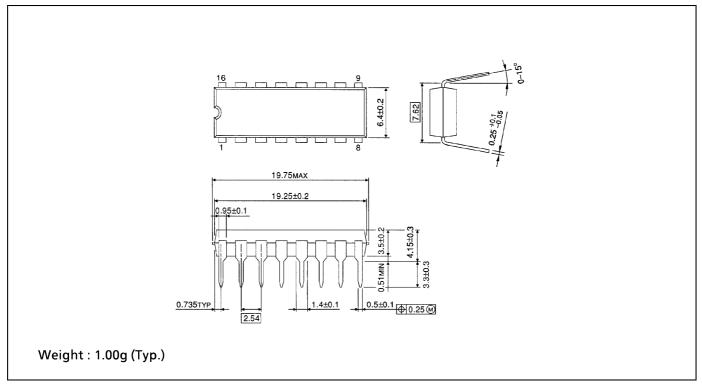
Average operating current can be obtained by the equation:

 I_{CC} (opr.) = $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/4$ (per F/F)

And the total C_{PD} when n pcs of Flip Flop operate can be gained by the following equation: C_{PD} (total) = 35 + 50 · n

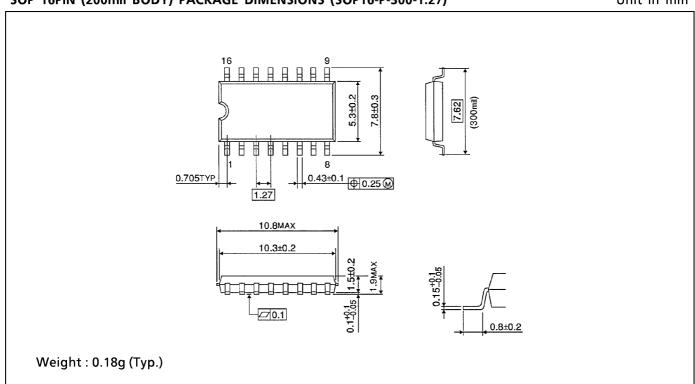
DIP 16PIN PACKAGE DIMENSIONS (DIP16-P-300-2.54A)

Unit in mm



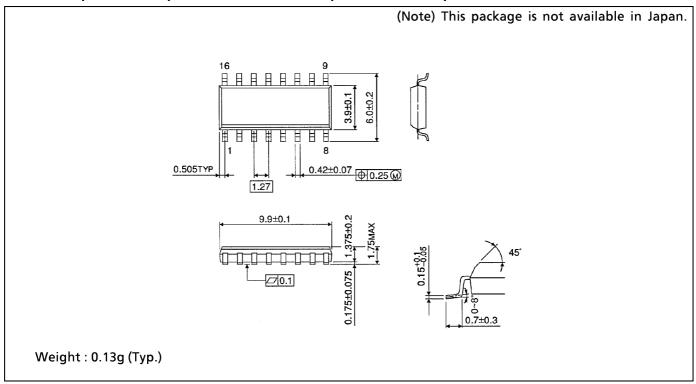
SOP 16PIN (200mil BODY) PACKAGE DIMENSIONS (SOP16-P-300-1.27)

Unit in mm



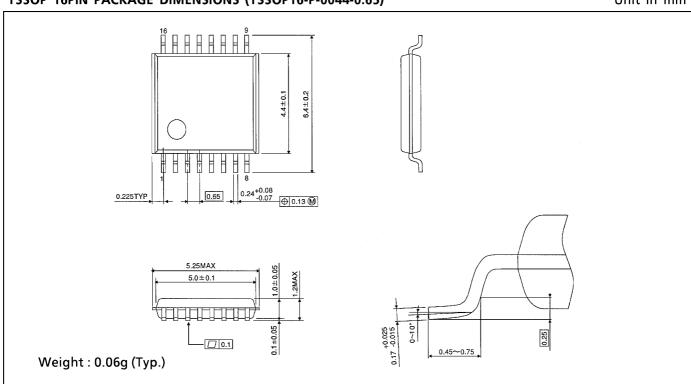
SOP 16PIN (150mil BODY) PACKAGE DIMENSIONS (SOL16-P-150 -1.27)

Unit in mm



TSSOP 16PIN PACKAGE DIMENSIONS (TSSOP16-P-0044-0.65)

Unit in mm



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